

Search Notes

Application/Control No.

10/822,570

Examiner

David E. Bochna

Applicant(s)/Patent under
Reexamination

HAGEN ET AL.

Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner
285	321	3/18/2007	DB
	98		
	374		
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	281		
	278		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
285	321	3/18/2007	DB
	374		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR